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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM 10017262	FILING DATE 12/14/2001	CLASS 250	SUBCLASS	GAU 2878	EXAMINER Johansen
**APPLICANTS: Adler David; Marcus Matthew;					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED:					
PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials				ATTORNEY DOCKET NO P960	
TITLE : Photoelectron emission microscope for wafer and reticle inspection					

U.S. DEPT. OF COMM./PAT. & TM.-PTO-426L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	Total Claims <input type="checkbox"/> Print Claim for O.G. <input type="checkbox"/>
ISSUE FEE		Primary Examiner	DRAWING
Amount Due	Date Paid		Sheets Drwg. <input type="checkbox"/> Figs. Drwg. <input type="checkbox"/> Print Fig. <input type="checkbox"/>
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner
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